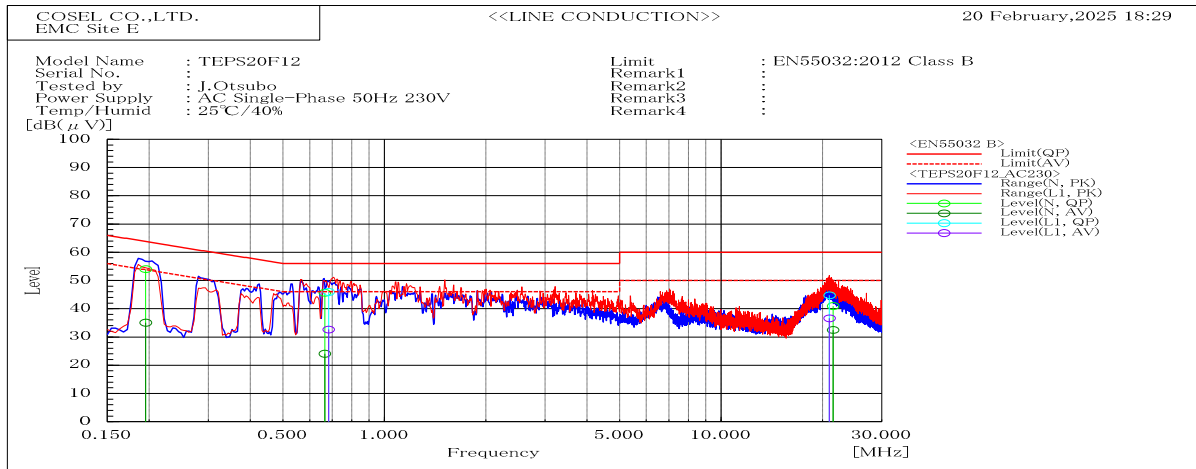
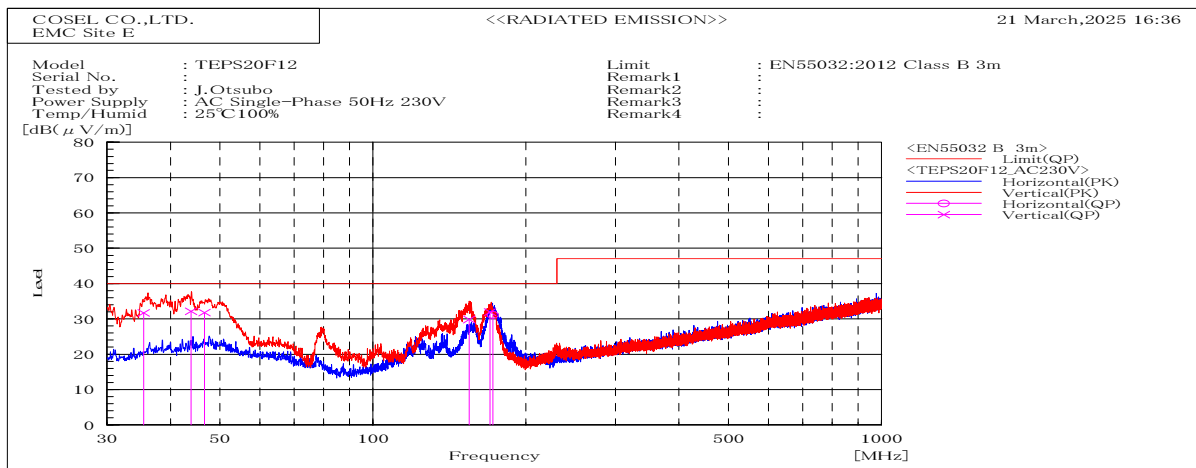


DATA SHEET		Date	24-Mar-25
Model	TEPS20F12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma



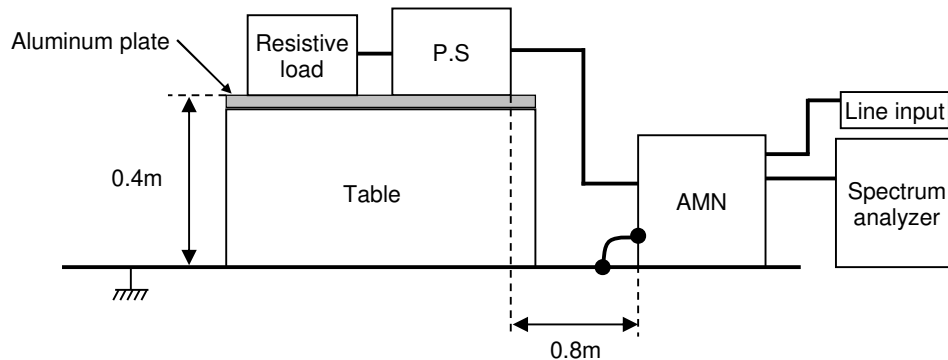
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.195	N	54	35	63.8	53.8	9.8	18.8	Pass	
0.666	N	45.6	24	56	46	10.4	22	Pass	
21.508	N	40.9	32.5	60	50	19.1	17.5	Pass	
0.683	L1	45.9	32.6	56	46	10.1	13.4	Pass	
20.974	L1	44.7	36.6	60	50	15.3	13.4	Pass	



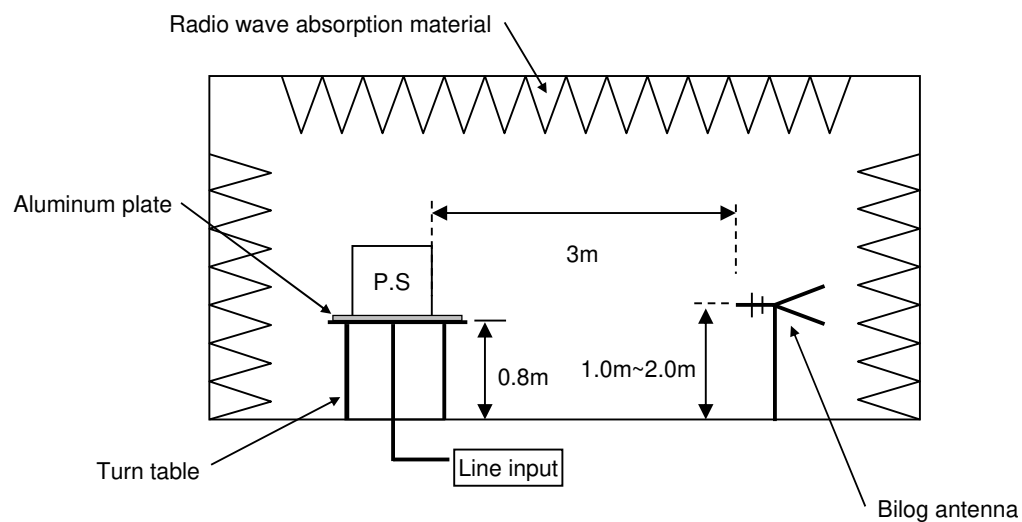
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP		cm	deg	
35.406	V	Stable	31.7	40	8.3	Pass	100.2	320.3	
43.888	V	Stable	32.2	40	7.8	Pass	100.2	217.1	
46.67	V	Stable	31.8	40	8.2	Pass	100.4	303.5	
154.561	V	Stable	29.9	40	10.1	Pass	100.4	30.6	
169.928	V	Stable	31.9	40	8.1	Pass	100.6	349.8	
172.045	H	Stable	31.1	40	8.9	Pass	160.4	356.9	

DATA SHEET		Date	24-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma

### 1. Line conduction



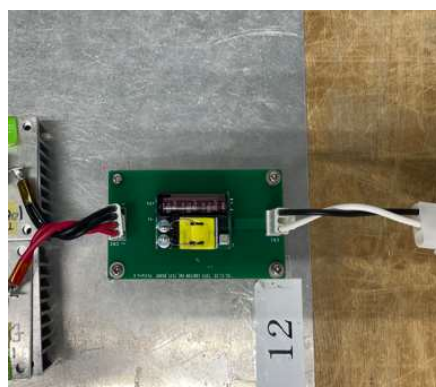
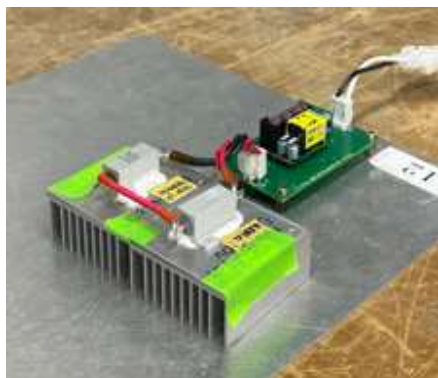
### 2. Radiated emission



## Conditions

Test : EMI  
Model Name : TEPS20F12

### 1.LINE CONDUCTION



### 2.RADIATED EMISSION

